



Theoretical analysis of integrated single-electron memory operation

A.N. Korotkov, J.Appl.Phys. 92, 7291 (Dec. 2002)

Single-electron memory vs. single-electron logic

- Much simpler architecture for memory
- Passive information storage vs. active information processing
- Easier temperature requirements for memory
- Random background charge OK for single-electron memory

Single-electron memory is much simpler for implementation than single-electron logic

Various meanings of “single-electron memory”

- Bit representation by one electron (or few electrons)
- Coulomb blockade for information storage
- Read-out by single-electron transistor



Single-electron or few-electron bit representation?

Advantages

- Fundamental limit
- Lowest energy dissipation
- Storage element as small as one atom
- No charging “tails” if fast

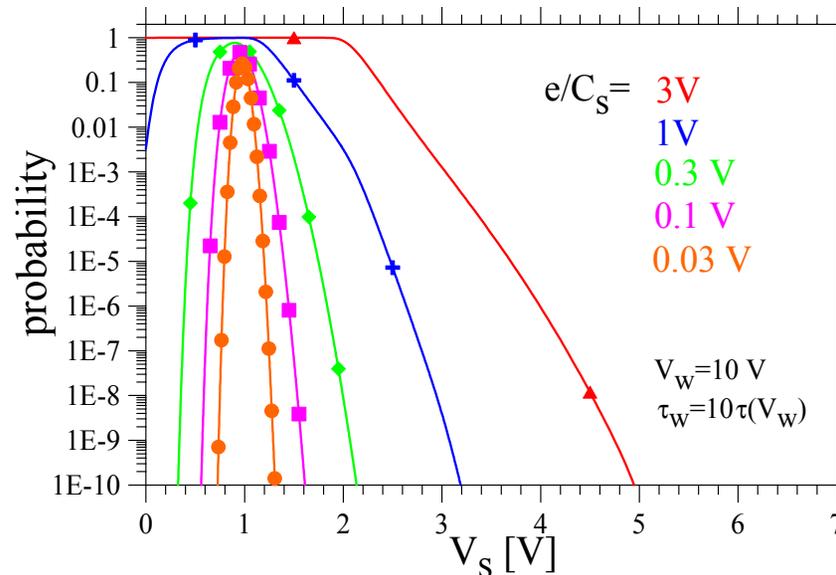
Disadvantages

- Information destroyed by single leakage event
- Error probability grows linearly with time
- Refreshing impossible

Best case: single-electron storage (using single atoms?!) but extra redundancy (either few one-electron elements in one memory cell or check sums)

Single-electron Fowler-Nordheim tunneling

Probability distribution of floating gate potential after charging (solid line: random background charge, symbols: $q_0 = -e/2$)



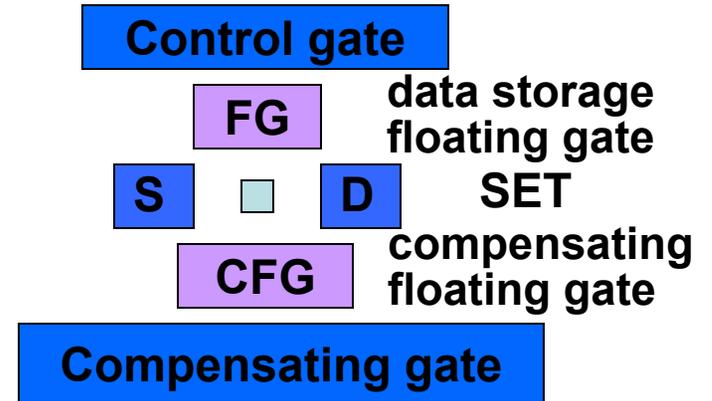
Two possible regimes:

either many electrons ($n > 10$) stored on the floating gate;
random background charge OK,

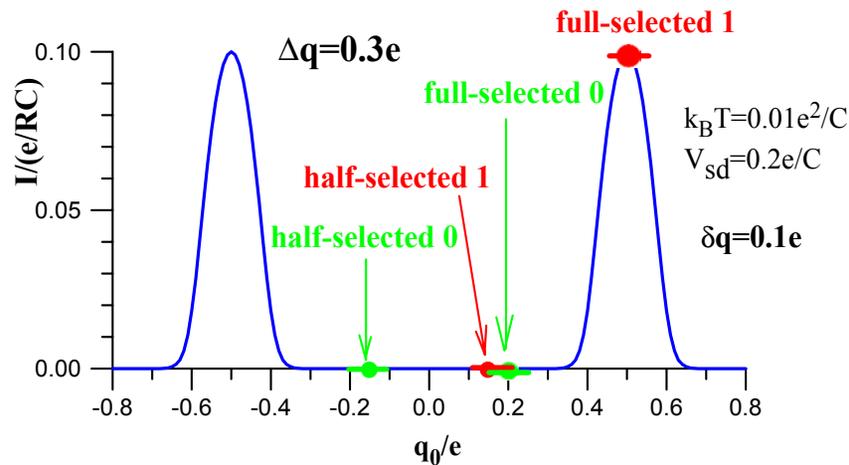
OR one electron; very long retention time for background
charge $q_0 = -e/2$

Few-electron (2-10) regime is bad (fluctuations are too large)

Background-charge-compensated SET readout



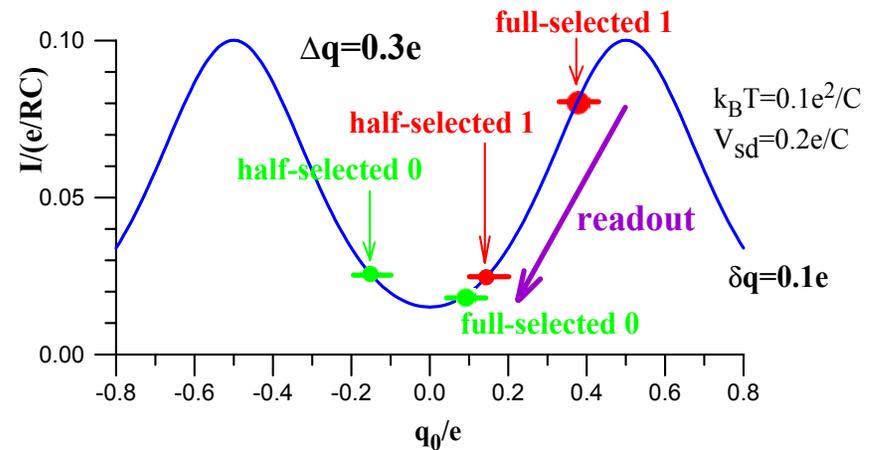
Nondestructive readout



SET operates as a switch

simpler

Destructive readout



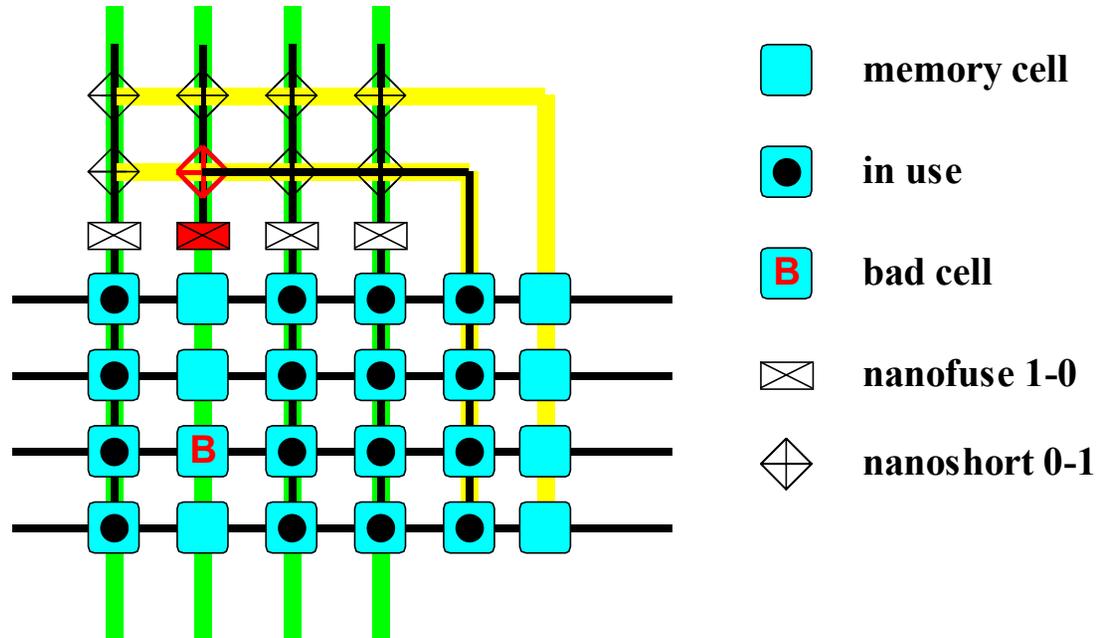
signals before and after erase compared

better SNR, higher T

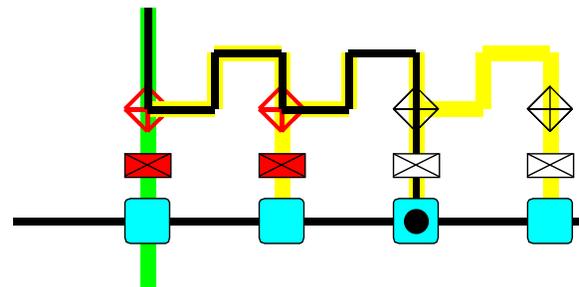
Defect-tolerant architecture based on nanofuses and nanoshorts

Idea: bit line rerouting
by blowing nanofuses
and activating nanoshorts

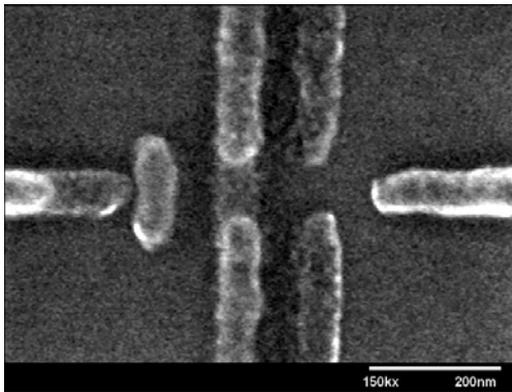
Needs reliable single-use
nanofuses and nanoshorts
(simple devices!)



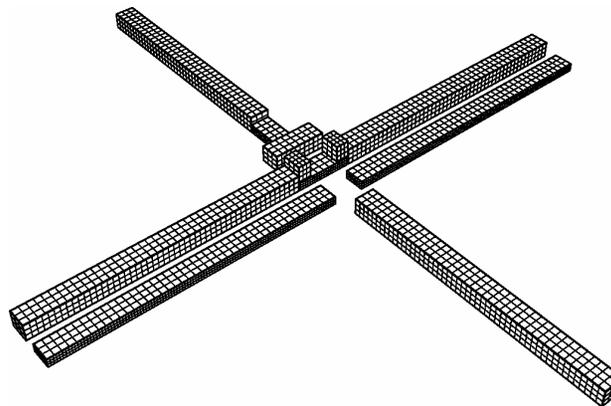
Works even for
low-yield cells:



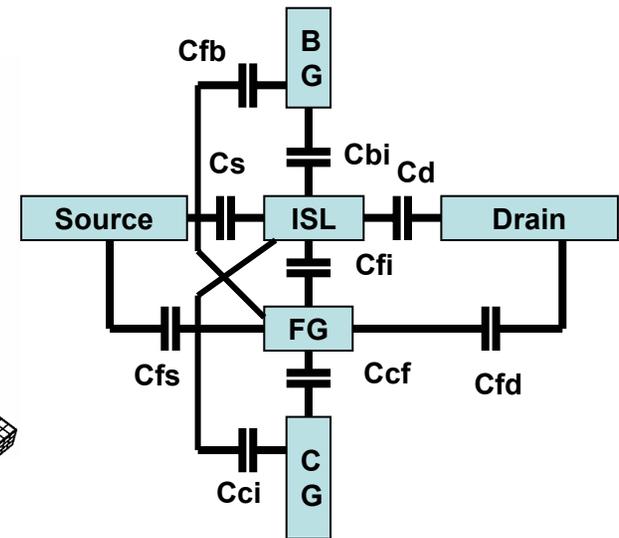
Calculating capacitance matrix by FASTCAP



U. Notre Dame

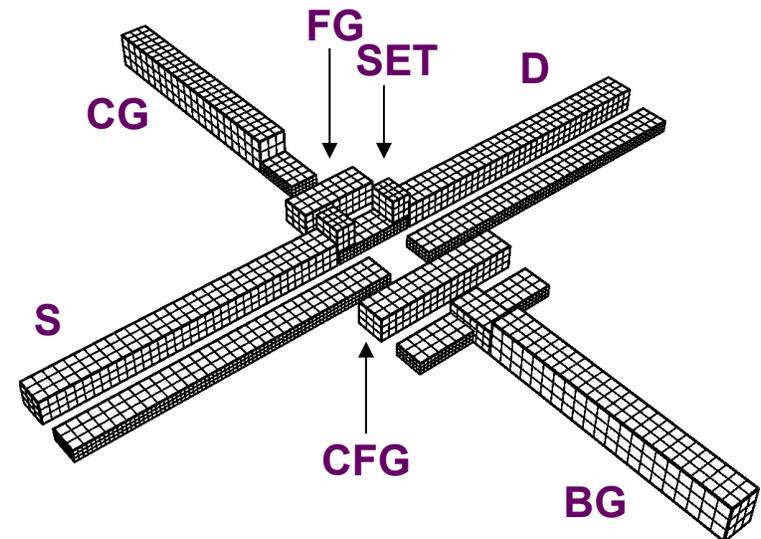


UC Riverside

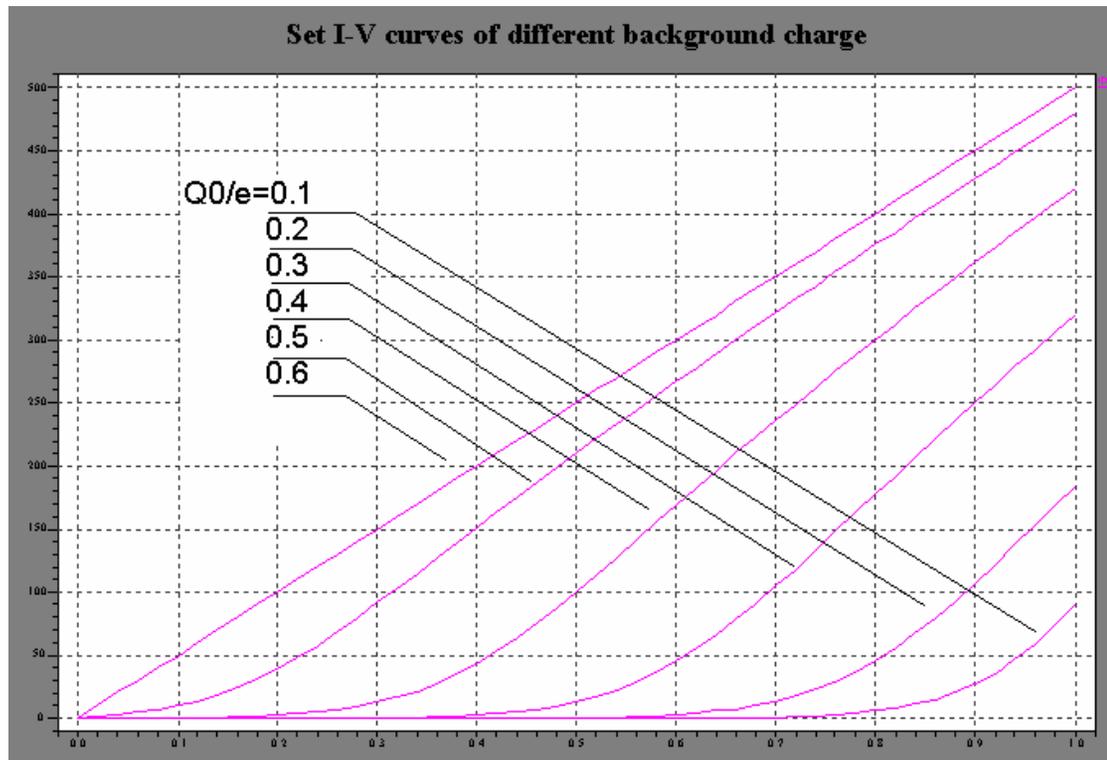
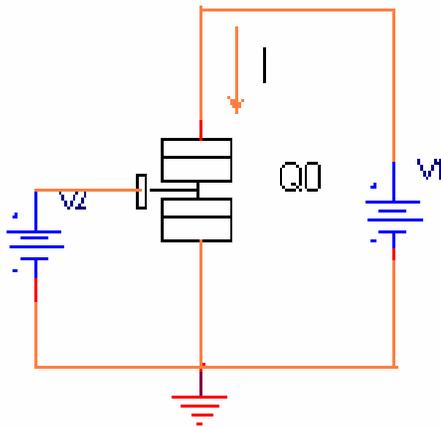


	$C_{ic,t}$	$C_{ib,t}$	C_{fi}/C_{ff}	V_g period
Theory	2.0 aF	0.69 aF	0.16	8 mV
ND exp	3.3 aF	0.73 aF	0.2	10 mV

Good agreement between theory and experiment



T-SPICE for SET circuits modeling

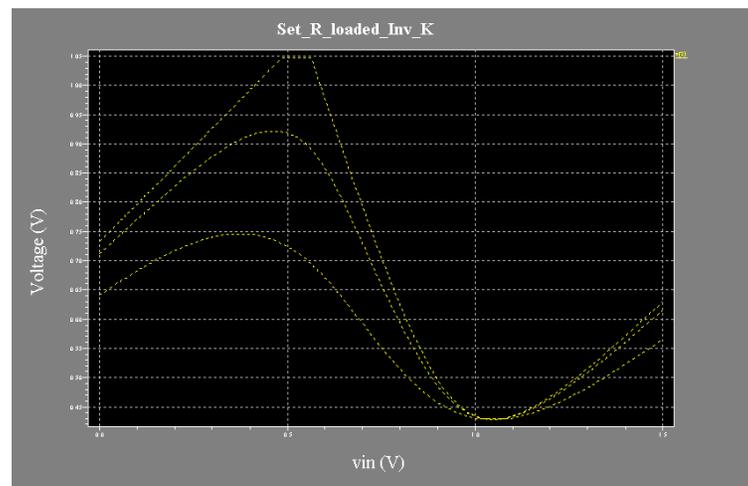
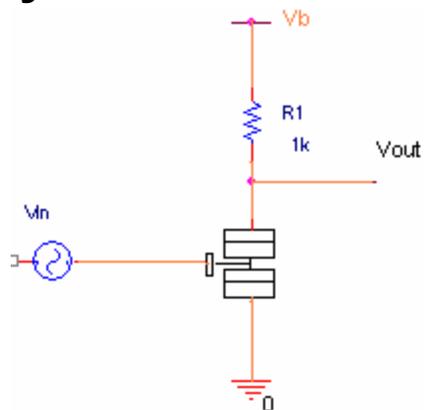


Full “orthodox” model for SET is used

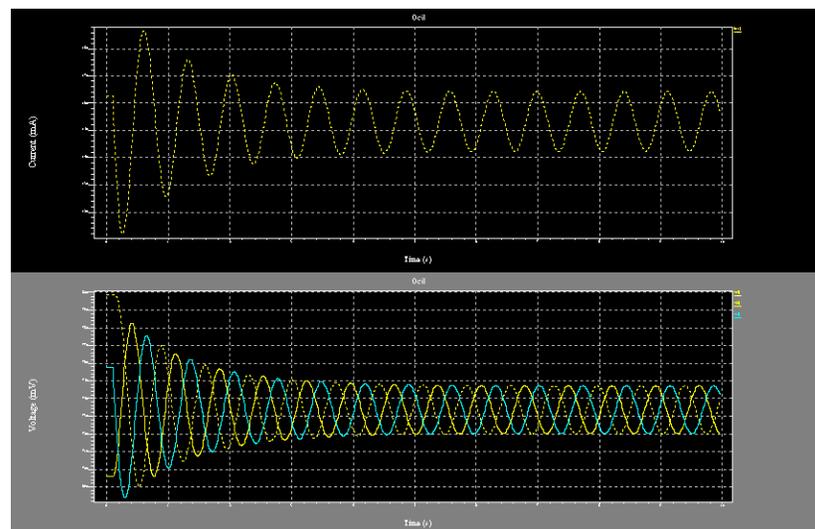
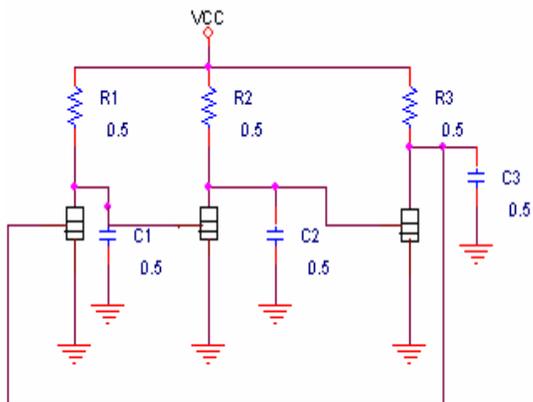
J. Yang, T. Gong, and A. Korotkov

T-SPICE modeling results

Resistively-loaded SET inverter



Ring oscillator with three SETs



**T-SPICE works for SET circuits,
but not very well**

J. Yang, T. Gong, and A. Korotkov